

National Bureau of Standards

Certificate

Standard Reference Material 4310

Mixed Gaseous Radioactivity Standard

Radionuclides	Xenon-133, Xenon-127, Krypton-85
Source identification	4310-
Source description	Gas in a sealed spherical borosilicate-glass ampoule (1)
Gas composition	Xenon-133, Xenon-127, Krypton-85, inactive xenon, inactive krypton, inactive CO ₂ (2)
Reference time	1200 EST April 15, 1982

Radionuclide	Activity at reference time Bq (s ⁻¹)	Total uncertainty (Random plus systematic)	
Xenon-133		1.55 percent	See xenon-133 data sheet
Xenon-127		1.71 percent	See xenon-127 data sheets
Krypton-85		2.51 percent	See krypton-85 data sheet

Photon-emitting impurity
 (Activity ratio at reference time)

^{131m}Xe/¹³³Xe: 0.103 ± 5% (3)

Half lives

¹³³Xe: 5.245 ± 0.006 days (4)
¹²⁷Xe: 36.41 ± 0.02 days (5)
⁸⁵Kr: 10.72 ± 0.01 years (6)

Measuring instrument

NBS pressurized "4π"γ ionization chamber A calibrated by internal gas-proportional counting

This Standard Reference Material was prepared in the Center for Radiation Research, Nuclear Radiation Division, Radioactivity Group, Dale D. Hoppes, Group Leader.

Washington, D.C. 20234
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Notes on back

FOOTNOTES

(1) Approximate ampoule specifications:

volume	30 cm ³
outside diameter	4.24 cm
wall thickness	0.19 cm

(2) Pressure - 101 kPa (760 Torr) \pm 20%.

(3) Limits of detection as a percentage of the gamma-ray-emission rate of the 81-keV gamma rays emitted in the decay of xenon-133 are

0.1 percent between 37 keV and 76 keV
0.01 percent between 86 keV and 1900 keV,

provided that impurity photons are separated in energy by 5 keV or more from the prominent photons emitted in the decays of xenon-133, xenon-127, and krypton-85.

(4) NCRP Report No. 58, 1978, p. 387.

(5) NCRP Report No. 58, 1978, p. 376.

(6) NCRP Report No. 58, 1978, p. 348.

Krypton-85
Data Sheet

- 1) Random uncertainty 0.23 percent

Half the 99-percent confidence interval of the mean (2.861 times the standard error computed from 20 ionization-chamber measurements).

- 2) Systematic uncertainty 2.28 percent

Linear sum of estimated uncertainty limits due to:

- a) calibration of the pressurized ^{85}Kr ionization chamber A, which is the linear sum of the estimated uncertainties due to:

- | | |
|---|--------------|
| 1) half the 99-percent confidence interval of the mean for 6 gas-counting measurements | 0.42 percent |
| 2) gram-mole measurements | 0.22 percent |
| 3) extrapolation of the gas-counting data | 0.2 percent |
| 4) dilution of sources for gas counting | 0.4 percent |
| 5) half the 99-percent confidence interval of the mean for 30 ionization-chamber measurements | 0.24 percent |
| 6) uncertainty in half life | 0.1 percent |
| 7) gas-transfer losses | 0.1 percent |
| 8) attenuation in glass | 0.2 percent |

- b) attenuation in glass walls of ampoule 0.2 percent

- c) gas-transfer losses 0.2 percent

- 3) When this source is used to measure the efficiency as a function of energy of a photon-spectrometer system, the attenuation in the glass walls of the 30.0-cm³ ampoule must be considered. The attenuation of 5.7 percent for the 0.514-MeV gamma ray was determined using a Ge(Li)-spectrometer system with a resolution of 1.28-keV full width at half maximum at 514 keV. For a germanium-spectrometer system of poorer resolution, or a NaI(Tl)-spectrometer system, the attenuation would be less than 5.7 percent.

(4)

DECAY SCHEME: NCRP REPORT NO. 58, p. 348, 1978

85KR B- DECAY (10.72 Y 1) I (MIN) = 0.10%

Radiation Type	Energy (keV)	Intensity (%)	Δ (g-rad/ μ Ci-h)
-----	-----	-----	-----
β^- 1 max	173.0 20		
avg	47.5 6	0.430 10	0.0004
β^- 2 max	687.0 20		
avg	251.4 8	99.570 10	0.533
total β^-			
avg	250.5 8	100.000 15	0.534
γ 1	513.990 10	0.430 10	0.0047

Xenon-133
Data Sheet

- 1) Random uncertainty 0.10 percent

Half the 99-percent confidence interval of the mean (2.861 times the standard error computed from 20 ionization chamber measurements).

- 2) Systematic uncertainty 1.45 percent

Linear sum of estimated uncertainty limits due to:

- a) calibration of pressurized $^{4\pi}\gamma$ ionization chamber A, which is the linear sum of the estimated uncertainty limits due to:

- 1) half the 99-percent confidence interval of the weighted mean of three series of gas-counting measurements 0.66 percent
- 2) extrapolation of the gas-counting data 0.22 percent
- 3) half the 99-percent confidence interval of the mean of three series of ionization-chamber measurements 0.01 percent
- 4) radium-226 reference sources ratios 0.36 percent

- b) Half life 0.20 percent

- 3) When this source is used to measure the efficiency as a function of energy of a photon-spectrometer system, the attenuation in the glass walls of the 30.0-cm³ ampoule must be considered. The attenuation, 11.3 percent, for the 0.081-MeV gamma ray was determined using a Ge(Li)-spectrometer system with a resolution of 1.00-keV full width at half maximum at 81 keV. For a germanium-spectrometer system of poorer resolution, or a NaI(Tl)-spectrometer system, the attenuation would be less than 11.3 percent.

(4)

DECAY SCHEME: NCRP REPORT NO. 58, p. 387, 1978

¹³³Xe B- DECAY (5.245 D 6) I (MIN) = 0.10%

Radiation Type	Energy (keV)	Intensity (%)	Δ (g-rad/ μ Ci-h)
Auger-L	3.55	49.0 20	0.0037
Auger-K	25.5	5.5 7	0.0030
ce-K- 1	43.636 11	0.30 6	0.0003
ce-K- 2	45.0124 4	52.0 3	0.0498
ce-L- 2	75.2827 4	8.49 20	0.0136
ce-MNO- 2	79.7799 4	2.3 3	0.0039
β^- 1 max	266 3		
avg	75.0 10	0.66 10	0.0011
β^- 2 max	346 3		
avg	100.5 10	99.34 10	0.213
total β^-			
avg	100.3 10	100.01 15	0.214
X-ray L	4.29	6.1 17	0.0006
X-ray $K\alpha_2$	30.6251 3	13.3 3	0.0087
X-ray $K\alpha_1$	30.9728 3	24.6 5	0.0163
X-ray $K\beta$	35	8.84 20	0.0066
γ 1	79.621 11	0.22 6	0.0004
γ 2	81	37.1 4	0.0640

4 weak γ 's omitted ($\Sigma I_\gamma = 0.07\%$)

Xenon-127
Data Sheet

- 1) Random uncertainty 0.22 percent

Half the 99-percent confidence interval of the mean (2.861 times the standard error computed from 20 ionization-chamber measurements).

- 2) Systematic uncertainty 1.49 percent

Linear sum of estimated uncertainty limits due to:

- a) calibration of the pressurized "4 " ionization chamber A, which is the linear sum of the estimated uncertainties due to:

- | | |
|---|--------------|
| 1) half the 99-percent confidence interval of the mean for 51 gas-counting measurements | 0.40 percent |
| 2) gram-mole measurements | 0.1 percent |
| 3) extrapolation of the gas-counting data | 0.2 percent |
| 4) dilution of sources for gas counting | 0.4 percent |
| 5) half the 99-percent confidence interval of the mean for 40 ionization-chamber measurements | 0.19 percent |
| 6) radium-226 reference ratios | 0.2 percent |

- 3) When this source and the data given in section 4 are used to measure the efficiency as a function of energy of a photon spectrometer system, the attenuation in the glass walls of the 30.0 cm³ ampoule should be considered. The attenuation corrections given in the table were determined with a Ge(Li)-spectrometer system with resolutions indicated in the table below and a source to detector distance of 25 cm. For a germanium-spectrometer system of appreciably poorer resolution, or a NaI(Tl)-spectrometer system, the tabulated attenuations would be maximum values.

Energy (keV)	Resolution (FWHM) (keV)	glass attenuation (%)
202.84	1.06	8.0
172.10	1.03	8.2
374.96	1.20	6.2
145.22	1.03	8.7
57.60	1.01	14.0

over

(4)

DECAY SCHEME: NCRP REPORT NO. 58, p. 376-377, 1978

127XE EC DECAY (36.41 D 2) I (MIN) = 0.10%

Radiation Type	Energy (keV)	Intensity (%)	Δ (g-rad/ μ Ci-h)
Auger-L	3.3	96 6	0.0068
Auger-K	23.6	12 3	0.0059
ce-K- 1	24.431 20	4.28 18	0.0022
ce-L- 1	52.412 20	0.61 3	0.0007
ce-M- 1	56.528 20	0.123 6	0.0001
ce-K- 2	112.05 3	1.54 6	0.0037
ce-K- 3	138.93 3	3.65 13	0.0108
ce-L- 2	140.03 3	0.391 14	0.0012
ce-L- 3	166.91 3	0.475 15	0.0017
ce-K- 4	169.67 3	6.63 8	0.0240
ce-L- 4	197.65 3	0.98 3	0.0041
ce-M- 4	201.77 3	0.198 3	0.0009
ce-K- 5	341.79 5	0.289 11	0.0021
X-ray L	4	10 4	0.0008
X-ray $K\alpha_2$	28.3172 4	25.1 10	0.0151
X-ray $K\alpha_1$	28.6120 3	46.7 17	0.0285
X-ray $K\beta$	32.3	16.4 7	0.0113
γ 1	57.600 20	1.33 6	0.0016
γ 2	145.22 3	4.29 14	0.0133
γ 3	172.10 3	25.5 8	0.0936
γ 4	202.84 3	68.3 5	0.295
γ 5	374.96 5	17.2 6	0.137

1 weak γ 's omitted ($\Sigma I\gamma = 0.01\%$)

- (5) CORRELATED SUMMING CORRECTIONS FOR THE 127XE ACTIVITY. NOTE; THE PEAK EFFICIENCY IS DENOTED BY "{ GAMMA RAY ENERGY }", THE TOTAL DETECTION EFFICIENCY IS DENOTED BY "(GAMMA RAY ENERGY)", AND "*" INDICATES MULTIPLICATION. "NO" REPRESENTS THE ACTIVITY AT THE MEASUREMENT TIME. IN MOST SYSTEMS, ONLY FIRST-ORDER EFFICIENCY TERMS NEED TO BE EVALUATED, AND THESE ARE GIVEN BELOW. IF THESE CORRECTIONS ARE LARGE(GREATER THAN 8%), THEN THE HIGHER ORDER TERMS MAY BE NEEDED. THESE ARE AVAILABLE UPON REQUEST.

FOR THE 202.84 KEV GAMMA RAY, THE PEAK AREA RATE IS EQUAL TO .6830*{ 202.84 }*NO*C1*C2

FACTOR FOR SUMMING IN EFFECTS

$$C1=[1.000 + .013*\{ 57.6 \}\{ 145.24 \}\{ 202.84 \}]$$

FACTOR FOR SUMMING OUT EFFECTS

$$C2=[1.000 - .778*(KX) - .311*(172.12)]$$

FOR THE 172.12 KEV GAMMA RAY, THE PEAK AREA RATE IS EQUAL TO .2550*{ 172.12 }*NO*C2

FACTOR FOR SUMMING OUT EFFECTS

$$C2=[1.000 - .853*(KX) - .016*(57.6) - .826*(202.84) - .051*(145.24)]$$

FOR THE 374.96 KEV GAMMA RAY, THE PEAK AREA RATE IS EQUAL TO .1720*{ 374.96 }*NO*C1*C2

FACTOR FOR SUMMING IN EFFECTS

$$C1=[1.000 + 1.169*\{ 202.84 \}\{ 172.12 \}\{ 374.96 \}]$$

FACTOR FOR SUMMING OUT EFFECTS

$$C2=[1.000 - .719*(KX)]$$

FOR THE 145.24 KEV GAMMA RAY, THE PEAK AREA RATE IS EQUAL TO .0429*{ 145.24 }*NO*C2

FACTOR FOR SUMMING OUT EFFECTS

$$C2=[1.000 - 1.366*(KX) - .209*(57.6) - .311*(172.12)]$$

FOR THE 57.6 KEV GAMMA RAY, THE PEAK AREA RATE IS EQUAL TO 0.0133*{ 57.6 }*NO*C2

FACTOR FOR SUMMING OUT EFFECTS

$$C2=[1.000 - .990*(KX) - .676*(145.24) - .311*(172.12)]$$